

Asylum Research, Inc. FM-AFM

- Asylum Research, Inc Fluorescence Atomic Force Microscope (FM-AFM) - combines Fluorescence-Atomic Force Microscope from Asylum Research, Inc. and the inverted Ti-E research Microscope from Nikon, Inc.
- Capability to pattern structures in the 10-100 nm region
- Designed to allow wet or dry measurements
- Dip Pen Lithography capability
- SPM modes and SNOM capabilities

